


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/711,637	CHEN ET AL.	
	Examiner	Art Unit	
	Tsz K. Chiu	2822	

SEARCHED			
Class	Subclass	Date	Examiner
257	49	1/20/2006	TKC
257	66-67	1/20/2006	TKC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (text search see attach)	1/20/2006	TKC